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| APPLICATION NO. | FILING DATE | FIRST NAMED INVENTOR | ATTORNEY DOCKET NO. | CONFIRMATION NO |
|---------------------------------------------------------------------------------|--------------------------------------------------|----------------------|---------------------|-----------------|
| 10/666,484 | 09/19/2003 | Subhas Bothra | PHA51101B 8867 | |
| 24738 | 7590 07/21/2004 | | EXAM | INER |
| PHILIPS ELECTRONICS NORTH AMERICA CORPORATION INTELLECTUAL PROPERTY & STANDARDS | | | STEIN, STEPHEN J | |
| | 1109 MCKAY DRIVE, M/S-41SJ SAN JOSE, CA 95131 | | ART UNIT | PAPER NUMBER |
| SAN JOSE, | | | 1775 | |

DATE MAILED: 07/21/2004

Please find below and/or attached an Office communication concerning this application or proceeding.

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| | Application No. | Applicant(s) |
| Office Action Summer | 10/666,484 | BOTHRA ET AL. |
| Office Action Summary | Examiner | Art Unit |
| The MAILING DATE of this security of | Stephen J Stein | 1775 |
| The MAILING DATE of this communication app Period for Reply | ears on the cover sheet with the c | orrespondence address |
| A SHORTENED STATUTORY PERIOD FOR REPLY THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1.13 after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above is less than thirty (30) days, a reply If NO period for reply is specified above, the maximum statutory period we Failure to reply within the set or extended period for reply will, by statute, Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b). | 36(a). In no event, however, may a reply be tin within the statutory minimum of thirty (30) day rill apply and will expire SIX (6) MONTHS from cause the application to become ABANDONE | nely filed s will be considered timely. the mailing date of this communication. D (35.U.S.C. 8.133) |
| Status | | |
| Responsive to communication(s) filed on | action is non-final. ace except for formal matters, pro | |
| Disposition of Claims | | |
| 4) ☐ Claim(s) 40-43 is/are pending in the application 4a) Of the above claim(s) is/are withdraw 5) ☐ Claim(s) is/are allowed. 6) ☐ Claim(s) 40-43 is/are rejected. 7) ☐ Claim(s) is/are objected to. 8) ☐ Claim(s) are subject to restriction and/or | vn from consideration. | |
| Application Papers | | |
| 9) The specification is objected to by the Examiner 10) The drawing(s) filed on is/are: a) access Applicant may not request that any objection to the of Replacement drawing sheet(s) including the correction of the original transfer of the property of the second of the second or declaration is objected to by the Examiner | epted or b) objected to by the lidrawing(s) be held in abeyance. See on is required if the drawing(s) is object. | e 37 CFR 1.85(a). jected to. See 37 CFR 1.121(d). |
| Priority under 35 U.S.C. § 119 | | |
| 12) Acknowledgment is made of a claim for foreign a) All b) Some * c) None of: 1. Certified copies of the priority documents 2. Certified copies of the priority documents 3. Copies of the certified copies of the prior application from the International Bureau * See the attached detailed Office action for a list of | s have been received. s have been received in Applicati ity documents have been receive (PCT Rule 17.2(a)). | on No ed in this National Stage |
| Attachment(s) 1) Notice of References Cited (PTO-892) 2) Notice of Draftsperson's Patent Drawing Review (PTO-948) 3) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08) Paper No(s)/Mail Date | 4) Interview Summary Paper No(s)/Mail Da 5) Notice of Informal P 6) Other: | |

DETAILED ACTION

Priority

1. Applicant has not complied with one or more conditions for receiving the benefit of an earlier filing date under 35 U.S.C. 120 as follows:

An application in which the benefits of an earlier application are desired must contain a specific reference to the prior application(s) in the first sentence of the specification or in an application data sheet (37 CFR 1.78(a)(2) and (a)(5)). The specific reference to any prior nonprovisional application must include the relationship (i.e., continuation, divisional, or continuation-in-part) between the applications except when the reference is to a prior application of a CPA assigned the same application number.

Specification

2. The specification is objected to as failing to provide proper antecedent basis for the claimed subject matter. See 37 CFR 1.75(d)(1) and MPEP § 608.01(o). Correction of the following is required: The limitation "conductive line" lacks antecedent basis in the specification.

Claim Objections

3. The claims are objected to since there is a duplicate claim 43.

Claim Rejections - 35 USC § 102

4. Claims 40, 41 and 43 are rejected under 35 U.S.C. 102(b) as being anticipated by US Patent US 5,792,707 (Chung).

Chung teaches a method for global planarization of integrated circuit structures using CMP (chemical mechanical polishing) with a polish stop layer (antireflective layer) (col. 1, lines

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6-10). Chung further teaches that the article to be polished includes a semiconductor substrate (10), a conductive metal material patterned to form conductive lines (14) (underlying patterned conductive line) on the substrate, a polish stop layer preferably composed of silicon nitride (26) (non-light transmissive anti-reflective material), and finally, a dielectric layer of silicon oxide (amorphous silica) or TEOS (30) (light transmissive dielectric layer) which is shown to be substantially aligned with and disposed above the underlying conductive lines (See Figures 1-5). Chung further teaches that the term substrate is understood to possibly include a semiconductor wafer (col. 3, lines 10-15).

Claim Rejections - 35 USC § 103

5. Claim 42 is rejected under 35 U.S.C. 103(a) as being obvious over Chung and further in view of US Patent 6,013,574 (Hause).

As stated above, Chung teaches an integrated circuit with a patterned anti-reflective polish stop layer over components, but does not specifically teach that the reflectance polish stop layer is amorphous silicon or silicon oxynitride.

Hause teaches an interconnect structure with an anti-reflective material on top of the conductive material. Hause further teaches that common anti-reflective materials include silicon oxynitride (SiON) and amorphous silicon (col. 2, lines 37-39). Consequently, it would have been obvious to one of ordinary skill in the art at the time of the invention to substitute SiON or amorphous silicon for the anti-reflective layer, because these materials are commonly known anti-reflective materials suitable for the same purpose.

Conclusion

6. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Stephen Stein whose telephone number is 572-272-1544. The examiner can normally be reached on Monday through Friday from 8:30 a.m. to 5:00 p.m. If the attempts to reach the examiner are unsuccessful, the examiner's supervisor, Deborah Jones can be reached by dialing 571-272-1535. The official fax number is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

July 16, 2004

Stephen J. Stein Primary Examiner

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